TOSHIBA Intelligent Power Device Silicon Monolithic Power MOS Integrated Circuit

# **TPD1034F**

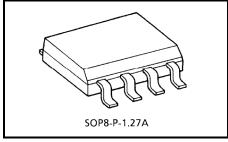
High-side Power Switch for Motors, Solenoids, and Lamp Drivers

The TPD1034F is a monolithic power IC for high-side switches. The IC has a vertical MOS FET output which can be directly driven from a CMOS or TTL logic circuit (e.g., an MPU). The device offers intelligent self-protection and diagnostic functions.

#### **Features**

- A monolithic power IC with a new structure combining a control block (Bi-CMOS) and a vertical power MOS FET (π-MOS) on a single chip.
- One side of the load can be grounded to a high-side switch.
- Can directly drive a power load from a microprocessor.
- Built-in protection against thermal shutdown and load short-circuiting.
- Incorporates a diagnosis function that allows diagnosis output to be read externally at load short-circuiting, opening, or overtemperature
- Up to −10 V of counter electromotive force from an L load can be applied.
- Low on-resistance  $: R_{ON} = 80 \text{ m}\Omega \text{ (max)}$
- Low operating current :  $I_{DD} = 1 \text{ mA (typ.)}, (@V_{DD} = 12 \text{ V}, V_{IN} = 0 \text{ V})$
- 8-pin SOP package for surface mounting can be packed in tape.

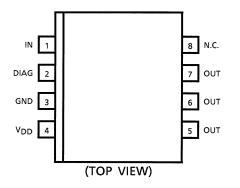
Note: Due to its MOS structure, this product is sensitive to static electricity. Handle with care.

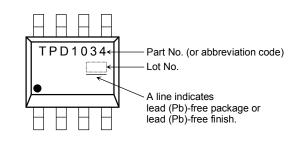


Weight: 0.08 g (typ.)

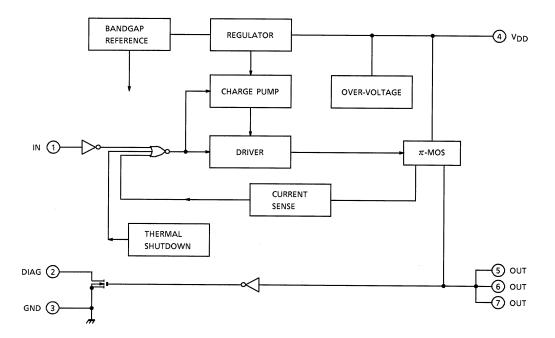
# Pin Assignment

# Marking





# **Block Diagram**

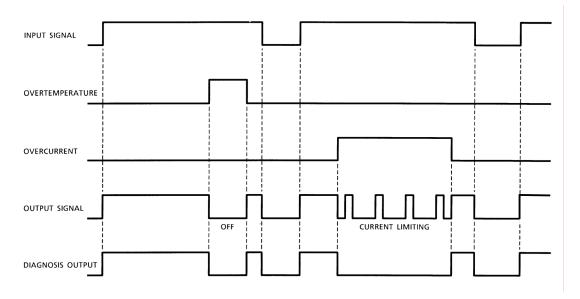


## **Pin Description**

Pin No.	Symbol	Function
1	IN	Input pin. Input is CMOS-compatible, with pull-down resistor connected. Even if the input is open, output will not accidentally turn on.
2	DIAG	Self-diagnosis detection pin. Goes low when overheating is detected or when output is short-circuited with input on (high). n-channel open drain.
3	GND	Ground pin.
4	$V_{DD}$	Power pin.
5, 6, 7	OUT	Output pin.  When the load is short circuited and current in excess of the detection current (24A typ.) flows to the output pin, the output automatically turns on or off.

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# Timing Chart



# **Truth Table**

Input Signal	Output Signal	Diagnosis Output	State	
Н	Н	Н	Normal	
L	L	L	Normal	
Н	L	L	Overcurrent	
L	L	L	Overcurrent	
Н	Н	Н	Load open	
L	Н	Н	Load open	
Н	L	L	Overtemperature	
L	L	L	Overtemperature	

## Absolute Maximum Ratings (Ta = 25°C)

Characteristic		Symbol	Rating	Unite
Drain-source voltage		V <sub>DS</sub>	60	V
Cupply voltage	DC	V <sub>DD (1)</sub>	25	V
Supply voltage	Pulse	V <sub>DD (2)</sub>	60 (Rs = 1Ω, τ= 250 ms)	V
Innut voltage	DC	V <sub>IN (1)</sub>	−0.5 ~ 12	V
Input voltage	Pulse	V <sub>IN (2)</sub>	V <sub>DD (1)</sub> + 1.5 (t = 100 ms)	V
Diagnosis output voltage		V <sub>DIAG</sub>	−0.5 ~ 25	V
Output current		Io	Internally limited	Α
Input current		I <sub>IN</sub>	±10	mA
Diagnosis output current		I <sub>DIAG</sub>	5	mA
Power dissipation (Ta = 25°C)		D	1.4 (Note 1)	w
		P <sub>D</sub>	2.4 (Note 2)	
Operating temperature		T <sub>opr</sub>	-40 ~ 110	°C
Channel temperature		T <sub>ch</sub>	150	°C
Storage temperature		T <sub>stg</sub>	<b>−</b> 55 ~ 150	°C

Note: Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings and the operating ranges.

Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/Derating Concept and Methods) and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

#### **Thermal Resistance**

Characteristic	Symbol	Test Condition	Unit	
Thermal resistance	D.,	89.3 (Note 1)	°C/W	
Thermal resistance	R <sub>th (ch-a)</sub>	52.1 (Note 2)	07W	

Note1: Mounted on a glass epoxy board (25.4 mm  $\times$  25.4 mm  $\times$  0.8 mm) (DC) Note2: Mounted on a glass epoxy board (25.4 mm  $\times$  25.4 mm  $\times$  0.8 mm) ( $t_W \le 10$  s)

## **Electrical Characteristics**

(Unless otherwise specified,  $T_{ch}$  = - 40 ~ 110°C,  $V_{DD}$  = 8 ~ 18 V)

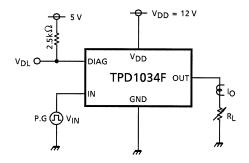
Characteristic		Symbol	Test Cir- cuit	Test Condition	Min	Тур.	Max	Unit
Operating supply volta	V <sub>DD (opr)</sub>	_	_	5	12	18	V	
Supply current		I <sub>DD</sub>	_	V <sub>DD</sub> = 12 V, V <sub>IN</sub> = 0	_	1	5	mA
lanut valtara		V <sub>IH</sub>	_	V <sub>DD</sub> = 12 V, I <sub>O</sub> = 8 A	3.5	_	_	V
Input voltage		V <sub>IL</sub>	_	V <sub>DD</sub> = 12 V, I <sub>O</sub> = 1.2 mA	_	_	1.5	V
Input current		I <sub>IN (1)</sub>	_	V <sub>DD</sub> = 12 V, V <sub>IN</sub> = 5 V	_	50	200	μA
		I <sub>IN (2)</sub>	_	V <sub>DD</sub> = 12 V, V <sub>IN</sub> = 0	-0.2	_	0.2	μΑ
On-voltage		V <sub>DS (ON)</sub>	_	V <sub>DD</sub> = 12 V, I <sub>O</sub> = 8 A, T <sub>ch</sub> = 25°C	_	_	0.64	V
On-resistance		R <sub>DS (ON)</sub>	_	V <sub>DD</sub> = 12 V, I <sub>O</sub> = 8 A, T <sub>ch</sub> = 25°C	_	_	0.08	Ω
Output leakage current		I <sub>OL</sub>	_	V <sub>DD</sub> = 18 V, V <sub>IN</sub> = 0	_	_	1.2	mA
Diagnosis output voltage	"L" Level	V <sub>DL</sub>	_	V <sub>DD</sub> =12 V, I <sub>DL</sub> = 2 mA	_	_	0.4	V
Diagnosis output current	"H" Level	I <sub>DH</sub>	_	V <sub>DD</sub> = 18 V, V <sub>DH</sub> = 18 V	_	_	10	μΑ
Overcurrent protection		I <sub>S (1)</sub> Note 3	1	V - 42 V T - 25°C	8	12	_	Α
		I <sub>S (2)</sub> Note 4	2	V <sub>DD</sub> = 12 V, T <sub>ch</sub> = 25°C	15	24	_	Α
Thermal shutdown	Temperature	Ts	_		150	160	200	°C
	Hysteresis	ΔTs	_	_	_	10	_	°C
Open detection resista	R <sub>ops</sub>	_	V <sub>DD</sub> = 8 V	1	50	100	kΩ	
Switching time		t <sub>ON</sub>	3	$V_{DD} = 12 \text{ V},  R_L = 5\Omega,$ $T_{ch} = 25^{\circ}\text{C}$	10	200	_	μs
		t <sub>OFF</sub>	3		10	30	_	μs

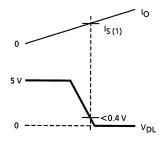
Note 3:  $I_{S(1)}$  denotes the overcurrent detection value when the load is short circuited and  $V_{IN}$  = "L"  $\rightarrow$  "H"

Note 4:  $I_{S(2)}$  denotes the overcurrent detection value when the load current is increased while  $V_{IN}$  = "H"

#### **Test Circuit 1**

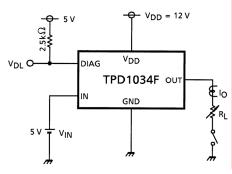
#### **Overcurrent detection**

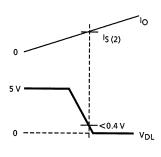




#### **Test Circuit 2**

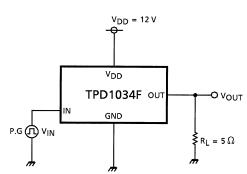
#### **Overcurrent detection**

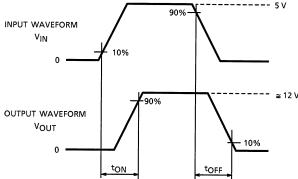


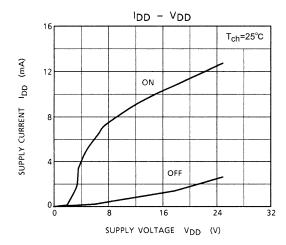


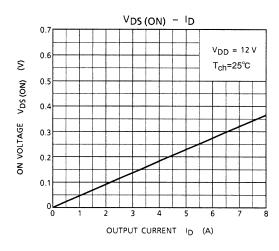
### **Test Circuit 3**

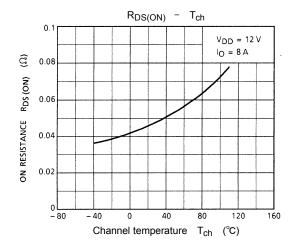
### Switching time

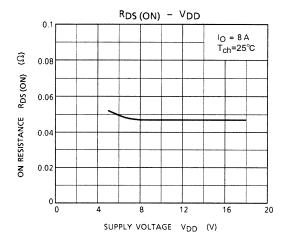


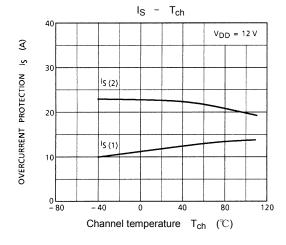


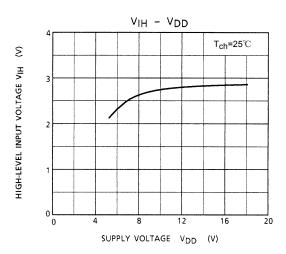


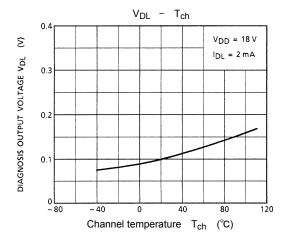


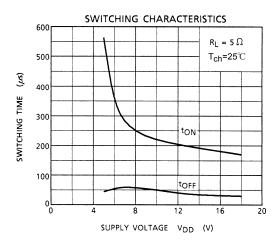


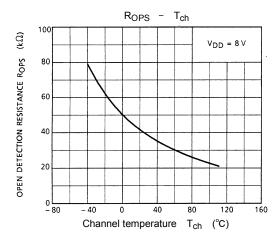


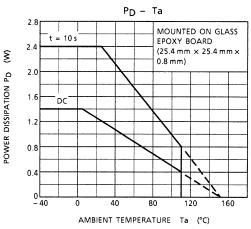


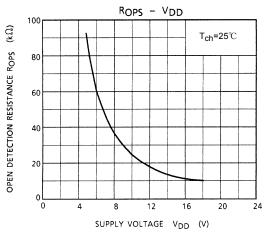










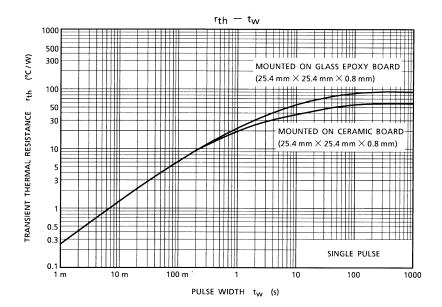


#### **Precaution:**

1. Since there is no built-in protection against reverse connection of batteries, etc., provide such protection using external circuits.

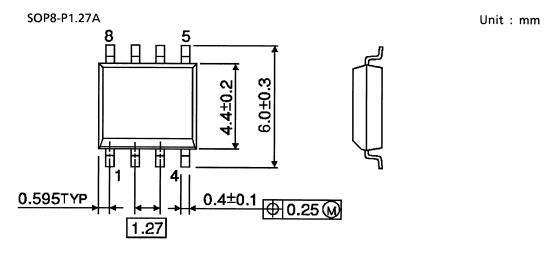
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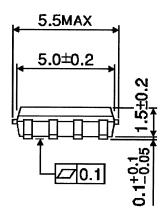
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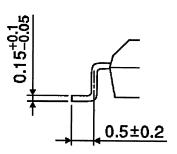


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# **Package Dimensions**







Weight: 0.08 g (typ.)

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